

**Defect Definitions**

Description	Definition	Class X Monochrome with microlens only	Class 0 Monochrome with microlens only	Class 1	Class 2 Color Only	Class 2 Monochrome Only	Notes	Test
Major dark field defective pixel	Defect $\geq 239$ mV	100	100	100	200	200	1,2	1
Major bright field defective pixel	Defect $\geq 15$ %						1,2	2
Minor dark field defective pixel	Defect $\geq 123$ mV	1000	1000	1000	2000	2000	1,2	1
Cluster defect	A group of 2 to "N" contiguous major defective pixels, but no more than "W" adjacent defects horizontally	0	1 N=10 W=3	20 N=10 W=3	20 N=10 W=3	20 N=12 W=5	1,2	
Column defect	A group of more than 10 contiguous major defective pixels along a single column	0	0	0	10	2	1,2	

**Notes:**

- There will be at least two non-defective pixels separating any two major defective pixels.
- Tested at 27°C and 40°C.

Class X sensors are offered strictly "as available". Kodak cannot guarantee delivery dates. Please call for availability.

**Defect Map**

The defect map supplied with each sensor is based upon testing at an ambient (27°C) temperature. Minor point defects are not included in the defect map. All defective pixels are reference to pixel 1,1 in the defect maps.